

Search Notes


Application/Control No.

10/691,705

Examiner

Sara W. Crane

 Applicant(s)/Patent under
Reexamination

HIRAMOTO, AKI

Art Unit

2811

SEARCHED

Class	Subclass	Date	Examiner
257	98 99 100	3/05	SWC
313	501 512		
362	311 800		
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update		12/05	SWC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
as above		12/05	SWC
(PGPUB included in text search)			

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

EAST	DATE	EXMR
chip and lens and (resin with expand) also	305	SWC
and (resin same space same expand)		
update See printout		